

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10773496	CHAN ET AL.
	Examiner	Art Unit
	Myhre, James W	3622

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
EAST Search (USPAT, US PgPub, JPO, EPO, DERWENT, IBM TB) (attached)	1/4/08	JWM

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner